

## MICROCIRCUIT DATA SHEET

Original Creation Date: 04/23/98 Last Update Date: 05/14/98 Last Major Revision Date: 04/23/98

# QUAD 2-INPUT NAND GATE

MNDM54LS00-X REV 1A0

## General Description

This device contains four independent gates, each of which performs the logic NAND function.

## Industry Part Number

NS Part Numbers

54LS00

DM54LS00E/883 DM54LS00J/883 DM54LS00W/883

## Prime Die

L000

### Processing

MIL-STD-883, Method 5004

## Quality Conformance Inspection

MIL-STD-883, Method 5005

# Subgrp Description Temp (°C) 1 Static tests at +25

2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

**Features** 

## (Absolute Maximum Ratings)

(Note 1)

Storage Temperature

-65 C to +150 C

Ambient Temperature under Bias

-55 C to +125 C

Input Voltage

-0.5V to +10.0V

VCC Pin Potential to Ground Pin

-0.5V to +7.0V

Junction Temperature under Bias

-55 C to +175 C Current Applied to Output in LOW state (Max)

twice the rated Iol (ma)

Note 1: Absolute Maximum ratings are those values beyond which the device may be damaged or

have its useful life impaired. Functional operation under these conditions is not implied.

## Recommended Operating Conditions

Free Air Ambient Temperature
Military
-55 C to +125 C

Supply Voltage
Military +4.5V to +5.5V

## **Electrical Characteristics**

#### DC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.) DC: VCC 4.5V to 5.5V, Temp range: -55C to 125C

SYMBOL	PARAMETER	CONDITIONS	NDITIONS NOTES		MIN	мах	UNIT	SUB- GROUPS	
IIH	Input High Current	VCC=5.5V, VM=2.7V, VINH=4.5V, VINL=0.0V	1, 3	INPUTS		20.0	uA	1, 2,	
IBVI	Input High Current	VCC=5.5V, VM=10.0V, VINH=4.5V, VINL=0.0V	1, 3	INPUTS		100	uA	1, 2,	
IIL	Input LOW Current	VCC=5.5V, VM=0.4V, VINH=4.5V	1, 3	INPUTS	-0.03	-0.4	mA	1, 2,	
VOL	Output LOW Voltage	VCC=4.5V, VIH=2.0V, IOL=4.0mA, VINH=4.5V	1, 3	OUTPUTS		0.4	V	1, 2,	
VOH	Output HIGH Voltage	VCC=4.5V, VIL=0.7V, IOH=-0.4mA, VINH=4.5V	1, 3	OUTPUTS	2.5		V	1, 2,	
IOS	Short-Circuit Current	VCC=5.5V, VINL=0.0V, VOUT=0.0V	1, 3	OUTPUTS	-20	-100	mA	1, 2,	
VCD	Input Clamp Diode Voltage	VCC=4.5V, IM=-18mA, VINH=4.5V	1, 3	INPUTS		-1.5	V	1, 2,	
ICCH	Supply Current	VCC=5.5V, VINL=0.0V	1, 3	VCC		1.6	mA	1, 2,	
ICCL	Supply Current	VCC=5.5V, VINH=4.5V	1, 3	VCC		4.4	mA	1, 2,	

## AC PARAMETER - 15pF

(The following conditions apply to all the following parameters, unless otherwise specified.) AC: CL=15pF, RL=2k ohms Temp range: +25C

tpLH	Propagation Delay	VCC=5.0V	5	In to On	10.0	ns	9
tpHL	Propagation Delay	VCC=5.0V	5	In to On	10.0	ns	9

#### AC PARAMETER - 50pF

(The following conditions apply to all the following parameters, unless otherwise specified.) AC: CL=50pF, RL=2k ohms Temp range: -55C to +125C

tpLH	Propagation Delay	VCC=5.0V	2, 4	In to On	2.0	15.0	ns	9
			2, 4	In to On	2.0	20.0	ns	10, 11
tpHL	Propagation Delay	VCC=5.0V	2, 4	In to On	2.0	17.0	ns	9
			2, 4	In to On	2.0	24.0	ns	10, 11

Note 1: Screen tested 100% on each device at -55C, +25C & +125C temperature, subgroups A1, 2,

3, 7 & 8.

Note 2: Screen tested 100% on each device at +25C temperature only, subgroup A9.

## (Continued)

- Note 3: Sample tested (Method 5005, Table 1) on each MFG. lot at +25C, +125C & -55C temperature, subgroups A1, 2, 3, 7 & 8.

  Note 4: Sample tested (Method 5005, Table 1) on each MFG. lot at +25C, subgroup A9. Subgroups 10 & 11 are guaranteed, not tested.

  Note 5: Guaranteed, not tested.

## Revision History

Rev	ECN #	Rel Date	Originator	Changes
1A0	M0001200	05/14/98		Initial release: MNDM54LS00-X Rev. 1A0 Added note 4 to the AC (50pF) notes reference column. Reworded note 4 from "and periodically at +125C & -55C, subgroups 10 & 11" to "Subgroups 10 & 11 are guaranteed, not tested". Changed the VOL test condition from VIL=2.0V to VIH=2.0V.